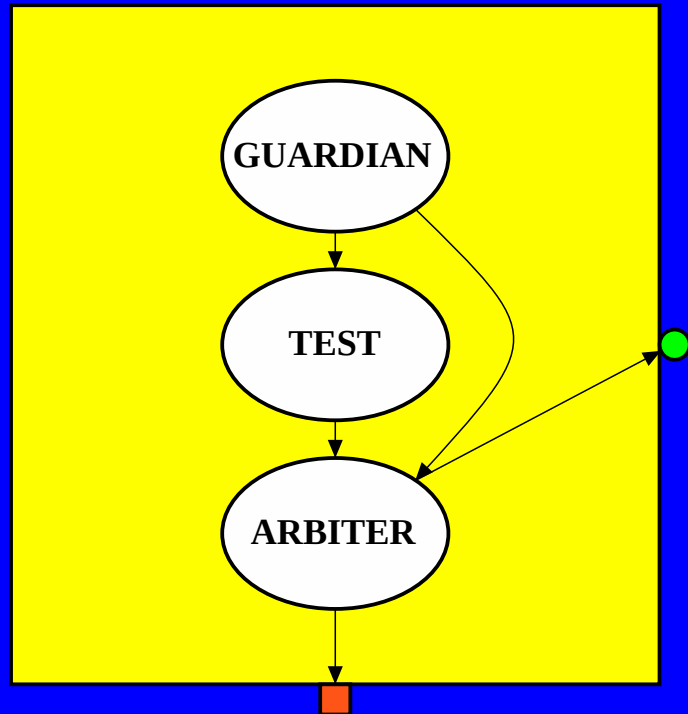


Test/Testblock/Testflow



Global Data

Pass Bins	120MHz	100MHz	80MHz	Indeterminate	...
Fail Bins	Speed	FunctionalDc	Diode		...
Flags	Enable Characterization Tests	Enable PowerScan Test	Enable FreqScan Test		...

Local Data

Pass/Fail

Parametric
Results